

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN#20221219002.1 Qualification of CDAT as an additional Assembly site for select devices Change Notification / Sample Request

Date: December 22, 2022

To: TOKYO ELECTRON DEVICE (DSTR) PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

Texas Instruments requires acknowledgement of receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If additional data is required, requests must be received within **30** days of this notification.

The changes discussed within this PCN will not take effect any earlier than the proposed first ship date on Page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the PCN Team (<u>PCN www admin team@list.ti.com</u>). For sample requests or sample related questions, contact your local Field Sales Representative.

Sincerely,

PCN Team SC Business Services

20221219002.1 Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the twentyfour (24) months. The corresponding customer part number is also listed, if available.

> **DEVICE** TPD4E02B04DQAR TPD4E05U06DQAR

CUSTOMER PART NUMBER

null null

Technical details of this Product Change follow on the next page(s).

| PCN Number: | 202 | 20221219002.1 PCN Date: Decembe 2022 | | | | | | December 2 2022 | 22, | | |
|---|---------------|--------------------------------------|---------------------------------|------------------------|-------------|-------------|-------------|---------------------------------------|---------------------|------------|--|
| Title: Qualification of CDAT as an alternate Assembly site for select devices | | | | | | | | | | | |
| Customer Contact: PCN Manager Dept: Quality Services | | | | | | | | | | | |
| Proposed 1 st | Ship Da | 22, 2023 | Sample Requests accepted until: | | | | | Jan 2 | 22, 2023* | | |
| *Sample requ | iests re | ceived afte | r Jan 22, | 2023 v | vill no | ot be sup | po | rted. | | | |
| Change Type | | | | | | | | | | | |
| | | | Desi | | | | | Wafer Bump Site | | | |
| Assembly | | | | Sheet | | | <u>Ц</u> | | Wafer Bump Material | | |
| Assembly | | | | number | <u>char</u> | nge | 닏 | Wafer Bump Process | | | |
| Mechanica Mechanica | • | | | Site | | | | Wafer Fab Site | | | |
| ☐ Packing/S | nipping/ | Labeling | ∟ Test | Proces | S | | + | Wafer Fab Materials Wafer Fab Process | | | |
| | | | D/ | CN Det | taile | | <u> </u> | ware | Гар | Piocess | |
| Description o | f Chang | A : | <u> </u> | CIT DE | ta 115 | | | | | | |
| Texas Instrum Assembly site | ents Inc | orporated is | | | | | | | | | |
| | | ASEN | C | CIRTEK | | JCETJY | | Y | CDAT | | |
| Mold Compound | SID | | | | S#12090 | 30 | 03709 | 4 | 1222198 | | |
| Mount Compound | SID | #140032911 | 1 SID#N | SID#NMS607CO10 S#12040 | | |)2007300 | | | 1207123 | |
| Bond wire composition diameter | ٦, | Au, 0.8 mil | Au | Au, 0.8 mil Au, | | Au, 0 | Au, 0.8 mil | | С | u, 0.8 mil | |
| Reason for Ch | nange: | | | | | | | | | | |
| Supply continu | | | | | | | | | | | |
| | | | | | .= | | | | _ | | |
| Anticipated in | npact o | n Form, Fit | , Functio | n, Qual | ity o | r Reliabili | ty | (positi | ve / r | negative): | |
| None | | | | | | | | | | | |
| Impact on En | vironm | ental Rating | js | | | | | | | | |
| Checked boxes change. If beloratings. | | | | | | | | | | | |
| RoHS | | REACH | | Green Stat | | | tus | | | C 62474 | |
| ☑ No Change | | ange | nge 🛛 No Chan | | | Change 🛛 | | | hange | | |
| | | inge La rie enange | | | | | | | | | |
| Changes to product identification resulting from this PCN: | | | | | | | | | | | |
| Assembly Sit | | assembly Site | | | mbly | Country C | od | e | Ass | embly City | |
| ASEN | | ASN | | | | CHN | | | | Suzhou | |
| CIRTEK | | CTK | | | | PHL | | | | inan City | |
| JCETJY | | JC8 | | | | CHN | | | | Jiangyin | |
| CDAT | | CDA | | | | CHN Chengdu | | | | | |
| CDAT | CDAT CDA CTIN | | | | | | mengau | | | | |

Sample product shipping label (not actual product label)

TEXAS
INSTRUMENTS
MADE IN: Malaysia
200:
MSL 2 /260C/1 YEAR SEAL DT
MSL 1 /235C/UNLIM 03/29/04

OPT:
ITEM:
ITEM:
JSP
LBL: 5A (L)T0:1750

Product Affected:

TPD4E02B04DQAR

TPD4E05U06DQAR

TI Information Selective Disclosure

Qualification Report Approve Date 29-September-2022

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

| Туре | # | Test Name | Condition | Duration | Qual Device: TPD4E05U06DQAR | QBS Reference: TPS2546QRTERQ1 | QBS Reference: TPD2E2U06QDCKRQ1 | QBS Reference: TPD4E05U06DQAR |
|-------|----|----------------------------------|-----------------------|------------|--------------------------------|----------------------------------|------------------------------------|----------------------------------|
| HAST | A2 | Biased HAST | 130C/85%RH | 96 Hours | - | 3/231/0 | - | - |
| HAST | A2 | Biased HAST | 130C/85%RH | 96 Hours | - | - | 3/231/0 | - |
| UHAST | A3 | Autoclave | 121C/15psig | 96 Hours | 3/231/0 | - | - | - |
| UHAST | A3 | Autoclave | 121C/15psig | 96 Hours | - | 3/231/0 | 3/231/0 | - |
| UHAST | A3 | Unbiased HAST | 130C/85%RH | 96 Hours | - | - | - | 3/231/0 |
| TC | A4 | Temperature Cycle | -55C/150C | 400 Cycles | - | - | 3/231/0 | - |
| TC | A4 | Temperature Cycle | -65C/150C | 500 Cycles | 3/231/0 | - | - | 3/231/0 |
| TC | A4 | Temperature Cycle | -65C/150C | 500 Cycles | - | 3/231/0 | - | - |
| HTSL | A6 | High Temperature Storage Life | (Dry bake at 150C) | 500 Hours | - | - | 3/15/0 | - |
| HTSL | A6 | High Temperature Storage Life | 150C | 1000 Hours | - | 3/135/0 | - | - |
| HTSL | A6 | High Temperature Storage Life | 170C | 420 Hours | 3/231/0 | - | - | 3/231/0 |
| HTOL | B1 | High Temperature Reverse Bias | 125C | 1000 Hours | - | - | 3/231/0 | - |
| HTOL | B1 | Life Test | 125C | 1000 Hours | - | 3/231/0 | - | - |
| ELFR | B2 | Early Life Failure Rate | 125C | 48 Hours | - | 1/800/0 | - | - |

| WBS | C1 | Ball Shear | 76 balls, 3 units min | Wires | 3/228/0 | - | - | - |
|------|------------|-----------------------------|---|-------------|---------|--------|--------|---------|
| WBP | C2 | Bond Pull | 76 Wires, 3 units min | Wires | 3/228/0 | - | - | 3/228/0 |
| SD | C3 | PB Solderability | Precondition w.155C Dry Bake (4 hrs +/- 15 minutes) | - | - | 1/15/0 | 1/10/0 | - |
| SD | C3 | PB-Free Solderability | Precondition w.155C Dry Bake (4 hrs +/- 15 minutes) | - | - | 1/15/0 | 1/10/0 | - |
| SD | C3 | PB-Free Solderability | 8 Hours Steam Age | - | - | - | - | 3/66/0 |
| PD | C4 | Physical Dimensions | (per mechanical drawing) | - | 3/15/0 | - | - | 3/15/0 |
| PD | C4 | Physical Dimensions | Cpk>1.67 | - | - | 3/30/0 | - | - |
| PD | C4 | Physical Dimensions | Cpk>1.67 | - | - | - | 1/30/0 | - |
| ESD | E2 | ESD CDM | - | 1500 Volts | - | - | - | 1/3/0 |
| ESD | E2 | ESD CDM | - | 1500 Volts | - | - | 1/10/0 | - |
| ESD | E2 | ESD CDM | - | 250 Volts | 1/3/0 | - | - | - |
| ESD | E2 | ESD CDM | - | 500 Volts | - | 1/3/0 | - | - |
| ESD | E2 | ESD HBM | - | 1000 Volts | 1/3/0 | - | - | - |
| ESD | E2 | ESD HBM | - | 10000 Volts | - | - | 1/10/0 | - |
| ESD | E2 | ESD HBM | - | 2000 Volts | - | 1/3/0 | - | - |
| ESD | E2 | ESD HBM | - | 6000 Volts | - | - | 1/10/0 | - |
| CHAR | E5 | Electrical Characterization | Per Datasheet Parameters | - | 1/30/0 | - | - | 1/30/0 |
| CHAR | E 5 | Electrical Distributions | Cpk>1.67 Room, hot, and cold | - | - | 3/90/0 | - | - |
| CHAR | E5 | Electrical Distributions | Cpk>1.67 Room, hot, and cold | - | - | - | 3/75/0 | - |

- QBS: Qual By Similarity
- Qual Device TPD4E05U06DQAR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- $\bullet \quad \text{The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles}\\$

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2205-019

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

| Location | E-Mail | | | | |
|---------------------------|--------------------------------|--|--|--|--|
| WW Change Management Team | PCN www admin team@list.ti.com | | | | |

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